

Search Notes**Application/Control No.**

10/606,547

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	531	3/25/2006	MK
	513, 529	3/25/2006	MK
707	102	3/25/2006	MK
719	316	3/25/2006	MK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search	3/25/2006	MK
West Search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/25/2006	MK
West Search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/31/2006	MK
Consulted with Primary William Bashore	3/31/2006	MK
NPL (IEEE)	3/31/2006	MK